

Gratings are available for lateral/vertical calibration, detection of lateral non-linearity, hysteresis, creep and cross-coupling effects, and determination of tip shape.



TDG01

Diffraction grating TDG01 is intended for submicron calibration scanning probe microscopes (SPM) in the X or Y direction.



TGG1

TGG calibration gratings are intended for AFM calibration in X or Y axis, detection of lateral and vertical scanner nonlinearity, detection of angular distortion, and tip characterization.



TGQ1

TGQ calibration gratings are intended for simultaneous calibration in X, Y, and Z directions, lateral calibration of AFM scanners, and detection of lateral nonlinearity, hysteresis, creep and cross-coupling effects.



TGT1

TGT calibration gratings allow users to visualize scanning tips in 3-D, determine tip sharpness parameters (aspect ratio and curvature radius), tip degradation and contamination control.



TGX1

TGX calibration gratings are intended for lateral calibration of AFM scanners, detection of lateral nonlinearity, hysteresis, creep and cross-coupling effects, and determination of the tip aspect ratio.



TGZ1, TGZ2, TGZ3, TGZ4

TGZ calibration grating series are intended for Z-axis calibration of scanning probe microscopes (SPM) and nonlinearity measurements.

GRATINGS AVAILABLE IN SETS

Set Name	Set Includes
TG\$1	TGZ1, TGZ2, and TGZ3.
TG\$1F	TGZ1, TGZ2, TGZ3, and TGZ4.
TGS1_PTB	TGZ1, TGZ2, TGZ3, and a PTB traceable certificate
TGS2	TGZ1, TGZ2, TGZ3, TGX1, TGG1, and TGT1.
TGSFULL	TGZ1, TGZ2, TGZ3, TGX1, TGG1, TGT1, and TGQ1.
TGS_CERT	TGZ1, TGZ2, TGZ3, TGG1, TGT1, TGQ1, and International Calibration Certificates.

Shop online at <u>www.kteknano.com</u> or contact us at: